

Notice of References Cited	Application/Control No. 10/584,052		Applicant(s)/Patent Under Reexamination POCAS ET AL.	
	Examiner ERIC W. JONES		Art Unit 2892	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,181,538 A	01-1980	Narayan et al.	438/473
*	B	US-4,577,396 A	03-1986	Yamamoto et al.	438/582
*	C	US-4,742,017 A	05-1988	Bredthauer, Richard A.	438/72
*	D	US-5,236,872 A	08-1993	van Ommen et al.	438/659
*	E	US-5,354,697 A	10-1994	Oostra et al.	438/514
*	F	US-5,528,058 A	06-1996	Pike et al.	257/142
*	G	US-5,654,241 A	08-1997	Kakumu, Masakazu	438/306
*	H	US-5,783,477 A	07-1998	Kish et al.	438/455
*	I	US-6,054,369 A	04-2000	Neilson et al.	438/455
*	J	US-6,274,892 B1	08-2001	Kub et al.	257/131
*	K	US-6,410,371 B1	06-2002	Yu et al.	438/151
*	L	US-2002/0157790 A1	10-2002	Abe et al.	156/334
*	M	US-2003/0057522 A1	03-2003	Francis et al.	257/566

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Sze et al, Physics of Semiconductor Devices 1st Ed. 1969, 2nd Ed. 1981, 3rd Ed. 2007, Sec. 3.6, pages 187-191
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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